

Charm Form Factors at CLEO-c CIPANP 2009

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Talk Outline

- Overview of Semileptonic Decays
- The CLEO-c Program
- Measurements of D $\rightarrow \pi ev$ and D $\rightarrow Kev$ Form Factors
 - Overview of Analysis
 - Extraction of Partial Rates
 - Form Factor Fits
 - Comparison with Theory
- Conclusion

Overview of Semileptonic Decays

A Semileptonic D Decay:



Pseudoscalar-to-pseudoscalar decay rates are approximated by:

$$\frac{d \Gamma(D \rightarrow Pe \nu)}{dq^2} = \frac{G_F^2 p^3}{24 \pi^3} |V_{cq}|^2 |f_+(q^2)|^2$$

$$\begin{bmatrix} q^2 = \text{invariant} \\ mass of W^* \end{bmatrix}$$
Experimental
Measurement of
rates gives access
to f_+(q^2)|V_{cq}|
CKM Matrix Element

Overview of Semileptonic Decays

Semileptonic decays provide two pieces of information:

• $f_{+}(q^2)|V_{cq}|$ + input from theory = CKM matrix elements

• $f_{+}(q^2)|V_{cq}|$ + CKM elements = semileptonic form factors

Importance of charm form factors:

- |Vub| measurements are an important constraint on CKM unitarity triangle
- Vub| is extracted from B → πev and requires form factor input from theory → Lattice QCD
- LQCD is providing increasingly precise theoretical predictions
- Tests of new LQCD techniques in heavy-to-light transitions are needed



Providing tests of Lattice QCD is a primary goal of CLEO-c

The CLEO-c Program

CESR: an e+e- storage ring located at Cornell in Ithaca, NY

- Began collisions in 1979 with COM energies of ~10 GeV
- CLEO studied a wide variety of Y and B decays between 1979 and 2003
- In 2003, accelerator was altered to run near charm production threshold
- CLEO-c data sample includes 818/pb of data taken at the ψ(3770) resonance (10.4 million D meson decays)



The CLEO-c Program

- The CLEO-c Detector
- Dual tracking chambers
 σp/p = 0.5% at 0.7 GeV
 Covers |cos θ| < 0.93
- Particle ID provided by:
 - RICH detector
 - dE/dx
- Csl calorimeter
 - σE/E = 5% at 100 MeV
 - π^0 mass resolution ~ 6 MeV
 - Aids electron ID



The CLEO-c Program

Tagged Analysis Technique

- D decays at ψ(3770) occur exclusively as part of DD pairs → enables "tagging"
- Fully reconstruct one D decay in a clean hadronic mode – the "tag"
- Search for the semileptonic decay opposite the tag
- Neutrino 4-vector can be inferred from missing energy and momentum
- CLEO uses an alternative untagged technique, but this talk focuses on tagged results

 $e^+e^- \rightarrow c \,\overline{c} \rightarrow D^0 \overline{D}^0$ $\overline{D}^0 \rightarrow K^+ \pi^-, D^0 \rightarrow K^- e^+ \overline{\nu}$



Overview of Analysis

Tagging enables a simple extraction of decay rates:



- Measure $\Delta \Gamma_{_i}$ for $D^0 \rightarrow \pi^{\pm} ev$ and $D^{\pm} \rightarrow \pi^0 ev$ in 7 q² bins
- Measure $\Delta \Gamma_i$ for $D^0 \rightarrow K^{\pm}ev$ and $D^{\pm} \rightarrow K^0ev$ in 9 q² bins
- In 3 D⁰ tag modes (Κπ, Κππ⁰, Κπππ)
- In 6 D[±] tag modes (Κππ, Κπππ⁰, Κ⁰π, Κ⁰ππ⁰, Κ⁰πππ, ΚΚπ)

Overview of Analysis

Observed yields are corrected by efficiencies to obtain true yields:

$$\Delta \Gamma_{i} = \int_{q_{low,i}^{2}}^{q_{high,i}^{2}} \frac{d\Gamma(D \rightarrow Pe\nu)}{dq^{2}} dq^{2} = \frac{N_{signal,i}}{\tau_{D} N_{tag}}$$



Partial Rate Extraction: Tag Yields

Tag Candidates formed from combinations of pions & kaons:

$D^0 \rightarrow K^+ \pi^-$	$D^- \rightarrow K^+ \pi^- \pi^-$	$D^{-} \rightarrow K^{0}\pi^{-}\pi^{0}$
$D^0 \rightarrow K^+ \pi^- \pi^0$	$D^{-} \rightarrow K^{+}\pi^{-}\pi^{-}\pi^{0}$	$D^- \rightarrow K^0 \pi^- \pi^- \pi^+$
$D^0 \rightarrow K^+ \pi^- \pi^+ \pi^-$	$D^{-} \rightarrow K^{0}\pi^{-}$	$D^- \rightarrow K^+ K^- \pi^-$

Backgrounds are suppressed with cuts on two variables:

$$\Delta E = E_{tag} - E_{beam}$$

Tag-side yields and efficiencies are extracted from Beam Constrained Mass distributions

$$ightarrow M_{BC} = \sqrt{E_{beam}^2 - P_{tag}^2}$$

Partial Rate Extraction: Tag Yields

Tag Yield Fits



Tag Fits to Data:

- Unbinned likelihood fits:
- Signal shape specially designed to take into account psi(3770) lineshape, ISR and momentum resolution effects
- Modified ARGUS background
- Tagging Efficiencies
 - Obtained by treating Monte Carlo samples as data

Partial Rate Extraction: Semileptonic Reconstruction

Semileptonic Candidates

- Formed from combinations of electrons and mesons
- Yields extracted from distributions of:

$$U = E_{miss} - |P_{miss}|$$

And binned in

$$q^2 = (E_e + E_v)^2 - |P_e + P_v|^2$$

Neutrino 4-vector is inferred from missing energy/momentum, constrained by U=0

$$E_{v} = E_{miss}$$

$$P_{\nu} = E_{miss} \hat{P}_{miss}$$

Partial Rate Extraction: $D^0 \rightarrow \pi^{\pm} ev$ Signal Yields

Example Signal Yield Fits: $D^0 \rightarrow \pi^{\pm} ev$:



data (points), Signal (clear), Kenu(light), pev (dark) Other(med gray)

Partial Rate Extraction: Signal Efficiencies

- Signal Efficiency Matrices:
- Efficiency matrices give efficiency and smearing

$$E_{ij} = rac{N_{Reconstructed,i+Generated,j}}{N_{Generated,j}}$$

- Obtained from Signal MC
 - Account for efficiency & smearing due to semileptonic and tag reconstruction
 - Off-diagonal elements introduce a small correlation across q² in the partial rate measurements

	Generated Bin								
econstructed Bin	0.420 0.007 0.001 0.000 0.000 0.000 0.000	0.012 0.430 0.008 0.001 0.001 0.000 0.000	0.000 0.015 0.448 0.012 0.001 0.001 0.000	0.000 0.000 0.014 0.457 0.012 0.001 0.000	0.000 0.000 0.000 0.014 0.464 0.011 0.000	$\begin{array}{c} 0.000\\ 0.000\\ 0.000\\ 0.000\\ 0.009\\ 0.469\\ 0.007 \end{array}$	0.000 0.000 0.000 0.000 0.000 0.007 0.469		
Ř	π	⁺ev/Kī	т Sign	al Eff	icienc	y Mati	rix .		

Partial Rate Extraction: D⁰ Mode Results

Partial Rate Results:



Partial Rates extracted via:

$$\Delta \Gamma_{i} = \int_{q_{low,i}^{2}}^{q_{high,i}^{2}} \frac{d\Gamma(D \to Pe\nu)}{dq^{2}} dq^{2} = \frac{\sum_{i} \epsilon_{ij}^{-1} N_{j}}{\tau_{D} N_{tag} / \epsilon_{tag}}$$

and averaged over tag modes

Partial Rate Extraction: D⁺ Mode Results

Partial Rate Results:



- Results agree well across tags in all modes
- Isospin conjugate pairs also agree well

Partial Rate Extraction: Systematics

- Systematic Uncertainties on the partial rates:
- Our general approach to systematic uncertainties:
 - For each source of systematic uncertainty and for each semileptonic mode, we construct a covariance matrix that
 - gives the uncertainties on each of the $\Delta \Gamma_i$ and
 - their correlations across q2
- One method of constructing covariance matrices: make one or several variations to the analysis & remeasure the partial rates:

 $\boldsymbol{M}_{ij} \!=\! \boldsymbol{\delta}(\boldsymbol{\Delta}\boldsymbol{\Gamma}_i)\boldsymbol{\delta}(\boldsymbol{\Delta}\boldsymbol{\Gamma}_j)$

where $\delta(\Delta\Gamma_i)$ is the change in $\Delta\Gamma_i$ given the analysis variation When several variations are made, the resulting matrices are summed

Summary of Systematics for $D \rightarrow K^{\pm}ev$:

	σ(ΔΓ1)	σ(ΔΓ2)	σ(ΔΓ3)	σ(ΔΓ4)	σ(ΔΓ5)	σ(ΔΓ6)	σ(ΔΓ7)	σ(ΔΓ8)	σ(ΔΓ9)
Number of Tags	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%
Fake Tags	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%	0.4%
Tracking	0.7%	0.7%	0.8%	0.8%	0.8%	0.9%	1.0%	1.3%	1.2%
Kaon ID	1.0%	1.0%	0.9%	0.9%	1.0%	0.7%	0.3%	-0.3%	0.5%
electron ID	0.4%	0.4%	0.4%	0.4%	0.5%	0.5%	0.4%	0.3%	0.2%
Signal Shape	0.2%	0.1%	0.1%	0.1%	0.1%	0.1%	0.1%	0.1%	0.2%
Backgrounds	0.2%	0.0%	0.2%	0.1%	0.1%	0.1%	0.0%	0.1%	0.4%
FSR	0.1%	0.1%	0.1%	0.0%	-0.1%	-0.2%	-0.2%	-0.3%	-0.3%
MC Form Factor	0.0%	0.0%	0.0%	0.0%	0.0%	0.0%	0.0%	0.0%	-0.1%
q2 smearing	0.6%	-0.1%	0.1%	-0.1%	-0.1%	-0.5%	0.1%	-0.6%	-2.0%
Total	1.4%	1.4%	1.4%	1.4%	1.5%	1.4%	1.3%	1.5%	1.5%
Stat. Uncertainty	2.0%	2.2%	2.3%	2.5%	2.7%	3.1%	3.6%	4.9%	8.4%

Systematic uncertainties are smaller than statistical uncertainties in all modes

Form Factor Fits

Overview of Form Factor Fits:

Given the partial rates and their covariance matrices, we fit them using:

$$\frac{d\Gamma(D \to Pe\nu)}{dq^2} = \frac{G_F^2 p^3}{24\pi^3} |V_{cq}|^2 |f_+(q^2)|^2$$

In each semileptonic mode, we use five parameterizations of $f_{\downarrow}(q^2)$

For nominal fits, we use the Becher-Hill series expansion with three parameters:

$$f_{+}(q^{2}) = \frac{1}{P(q^{2})\phi(q^{2},t_{0})} \sum_{k=0}^{\infty} a_{k}(t_{0}) [z(q^{2},t_{0})]^{k}$$

For comparison with LQCD, we use the BK "modified pole" model:

$$f_{+}(q^{2}) = \frac{f_{+}(0)}{(1 - \frac{q^{2}}{m_{D^{*}}^{2}})(1 - \alpha \frac{q^{2}}{m_{pole}^{2}})}$$

Form Factor Fits



Comparison with Theory

Form factor normalization results:



- Results from this work are taken from isospin-combined fits using 3-parameter series expansion fits
- Agree with other experiments to within 2 sigma
- No discrepancy with LQCD at current level of precision

Comparison with Theory

Further Comparison with LQCD:



LQCD Fit/Bands courtesy Andreas Kronfeld, based on Fermilab Lattice/MILC/HPQCD Unquenched results (PRL 94, 011601 (2005))

- Points show CLEO's binned form factors with statistical & systematic uncertainties
- Solid line shows fit to unquenched LQCD (using modified pole model) with statistical (grey) and systematic (yellow) uncertainties



CKM Parameters

CKM Results:



- Results are dominated by theoretical uncertainty due to LQCD
- Within large uncertainties, consistent with other measurements and with PDG fits assuming CKM unitarity

Conclusion

- CLEO-c has measured partial rates in several q² bins for the semileptonic decays $D \rightarrow \pi^{\pm} ev$, $D \rightarrow K^{\pm} ev$, $D \rightarrow \pi^{0} ev$ and $D \rightarrow K^{0} ev$
- The partial rates have been used to extract form factors parameters and |V_{cd}| and |V_{cs}|
- Many of the form factor results are the world's most precise and provide a excellent goal for Lattice QCD

Backup Slides

Comparison with Theory

Form factor shape parameter results:



- All results use the modified pole model
- Results from this work are taken from isospin-combined fits
- Agree with other experiments to within 2 sigma

Branching fraction results (in %):

	This Work	CLEO-c 281/pb	BES II	Belle	BABAR
$D^0 \rightarrow \pi e v$	0.289(8)(3)	0.304(11)(5)		0.279(27)(16)	
$D^0 \rightarrow Kev$	3.51(3)(5)	3.60(3)(6)	3.82(40)(27)	3.45(10)(19)	3.52(3)(5)(7)
$D^{-} \rightarrow \pi^{0} ev$	0.41(2)(1)	0.38(2)(1)			
$D^{-} \rightarrow K^{0}ev$	8.83(10)(19)	8.69(12)(19)	8.71(38)(37)		

- Results from this work are taken from fits using 3 parameter series expansion
- Our results agree well with other experimental results and are signicantly more precise

Partial Rate Extraction: $D^0 \rightarrow K^{\pm}ev$ Signal Yields



- Signal shapes are wider in data \rightarrow MC smeared using a double Gaussian
- Smear Parameters are those that minimize LL summed over all tags/q2

Partial Rate Extraction: $D^{\pm} \rightarrow K^{0}ev$ Signal Yields



- Signal shapes are wider in data \rightarrow MC smeared using a double Gaussian
- Smear Parameters are those that minimize LL summed over all tags/q2

Partial Rate Extraction: $D^0 \rightarrow \pi^{\pm} ev$ Signal Yields



- Signal shapes are wider in data → MC smeared using a double Gaussian
- Smear Parameters are those that minimize LL summed over all tags/q2
- Fixed K[±]enu backgrounds also minimize by LL summed over all tags/q2

Partial Rate Extraction: $D^+ \rightarrow \pi^0 ev$ Signal Yields



- Signal shapes are wider in data → MC smeared using a double Gaussian
- Smear Parameters are those that minimize LL summed over all tags/q2
- Fixed K⁰enu backgrounds also minimize by LL summed over all tags/q2

Partial Rate Extraction: Systematics Example

An example: Background Shapes

- We vary each of the main background constituents in U fits within uncertainties on branching fractions and remeasure ΔΓ
- Solution E.g. in $D \to \pi^{\pm} ev$
 - Three backgrounds with fixed normalization:
 - Non-DD: varied by ± 20%
 - K±ev: varied by 8%
 - pev: varied by ±12%



 $D \to \pi^{\pm} ev$ Candidates in MC

Change in Partial Rates:

		Δ(ΔΓ1)	Δ(ΔΓ2)	Δ(ΔΓ3)	Δ(ΔΓ4)	Δ(ΔΓ5)	Δ(ΔΓ6)	Δ(ΔΓ7)
<u>ک</u> ہے	rhoenu+	-0.1%	-0.2%	-0.2%	-0.2%	-0.2%	-0.2%	-0.2%
ы	rhoenu-	0.1%	0.2%	0.2%	0.2%	0.2%	0.2%	0.2%
atio	cont+	-0.1%	-0.1%	0.0%	0.0%	-0.1%	-0.1%	0.0%
Ľ.	cont-	0.2%	0.1%	0.0%	0.0%	0.1%	0.1%	0.0%
Ц Ю	Kenu+	-0.3%	-0.3%	-0.2%	-0.3%	-0.2%	-0.1%	-0.1%
F.	Kenu-	0.2%	0.2%	0.1%	0.2%	0.2%	0.1%	0.1%